IBIS MODEL FORMULATION AND EXTRACTION FOR SPI EVALUATION

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PRESENTATION OUTLINES

I.IBIS Static Extension : BIRD-98,3

I.1 Linear Interpolation The Gate Modulation Functions II.IBIS Dynamic Extension : BIRD-95.6 II.2 Corrected IBIS BIRD 95.6 implementation III.Model Numerical Results

III.2 Model Simulation Performance

IV.Conclusions

TBIS STATIC EXTENSION : BIRD-98,3

 Driver's IBIS model element for the pull-up (PU) and pull-down (PD) network.



✓ Extracting the gate modulation effect functions:

$$G_{dd}(V_{dd}) = \frac{I_{dd}(V_{dd})}{I_{dd,sat}}$$
$$G_{ss}(V_{ss}) = \frac{I_{ss}(V_{ss})}{I_{ss,sat}}$$

DC voltage sweep while the PU and PD are active and in saturation. The recorded output power and ground (PG) dc currents is then normalized to their saturation currents *I_{ad,sat}* and *I_{ss,sat}*, respectively [3].

 $I_{2}(t) = K_{u}^{n}(t) \cdot G_{u}(V_{dd}(t)) \cdot F_{u}(V_{pu}(t), d/dt)$ $+ K_{d}^{n}(t) \cdot G_{d}(V_{ss}(t)) \cdot F_{d}(V_{pd}(t), d/dt) ; n = r, f$

LINEAR INTERPOLATION THE G(•) FUNCTIONS

✓ Example of the $G(\cdot)$ functions extracted for the PU and PD networks and their linear interpolation (dashed line).



✓ First order interpolation of the nonlinear static (*dc*) part of the $F_u(\cdot)$ and $F_d(\cdot)$ functions

$$F_{u}^{dc} \left(V_{1} = V_{DD}, V_{pu}(t) \right) \cong \frac{V_{dd}(t) - V_{DD2}}{V_{DD1} - V_{DD2}} \cdot F_{u}^{dc} \left(V_{2}(t), V_{DD1} \right) + \frac{V_{dd}(t) - V_{DD1}}{V_{DD2} - V_{DD1}} \cdot F_{u}^{dc} \left(V_{2}(t), V_{DD2} \right) F_{d}^{dc} \left(V_{1} = 0, V_{nd}(t) \right) \cong \frac{V_{ss}(t) - V_{ss2}}{V_{ss2}} \cdot F_{d}^{dc} \left(V_{2}(t), V_{ss1} \right)$$

$$\frac{dc}{d} \left(V_1 = 0, V_{pd}(t) \right) \cong \frac{V_{ss}(t) - V_{ss2}}{V_{ss1} - V_{ss2}} \cdot F_d^{dc} \left(V_2(t), V_{ss1} \right)$$

$$+ \frac{V_{ss}(t) - V_{ss1}}{V_{ss2} - V_{ss1}} \cdot F_d^{dc} \left(V_2(t), V_{ss2} \right)$$

- The DC I-V curves of the $F_u^{dc}(.)$ for fixed V_{DD1} and V_{DD2} can be extracted directly from the (typ, min, max) corners in the IBIS model.
- Additional I-V curves can be added to the PD network for different V_{ss1} and V_{ss2} values to model the $F_d^{dc}(.)$.

IBTS DYNAMIC EXTENSION : BIRD-95.6

Simulation setup for the power current I-t measurements $I_{com}^{dyn}(t) = I_{dd}^{TL}(t) - I_{dd}^{IBIS}(t)$



- ✓ RLC impedance extracted through AC sweep while the driver's input is kept at *H* and *L* levels and driving the load (*c*).
- ✓ Three different loading conditions (load (*a*) 50Ω, load (*b*) $50\Omega + V_{DD}$, and load (*c*)1MΩ)

✓ BIRD 95.6 presents a correction term only for the power $I_{dd}(t)$ current and has overlooked the ground $I_{ss}(t)$ current.

✓ The six $I_{com}(t)$ currents, in fact, model both the missing dynamic current at the PU and PD devices $(I_{dd}^{dyn}(t) = I_{ss}^{dyn}(t))$ which leads to an incorrect formulation for predicting the ground currents and therefore the $V_{ss}(t)$.

IBIS BIRD 95.6 MODEL IMPLEMENTATION

✓ RLC impedance can also be represented by the impulse response $h_u(t)$ and $h_d(t)$ between the PG ports (e.g. $p(t) = V_{dd}(t) - V_{ss}(t)$).

✓ The BIRD 95.6 implementation is illustrated in this
 Figure [6] and formulated in the time domain as follows:

$$I_{2}(t) = K_{u}^{n}(t) \cdot F_{u}(V_{pu}(t), d/dt)$$

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$$\int_{0}^{+\infty} h_{u}(t-\tau) \cdot p(\tau)d\tau + \int_{0}^{+\infty} h_{d}(t-\tau) \cdot p(\tau)d\tau$$

+
$$K_{d}^{n}(t) \cdot F_{d}(V_{pd}(t), d/dt) + I_{com}^{dyn,n}(t); n = r, f$$



CORRECTED IBIS BIRD 95.6 IMPLEMENTATION

 A more consistent model extraction and formulation should consider a timing current correction terms for both the PU and PD networks, respectively.

$$\begin{cases} I \frac{dyn}{dd,com}(t) = I_{dd}^{TL}(t) - I_{dd}^{IBIS}(t) \\ I \frac{dyn}{ss,com}(t) = I_{ss}^{TL}(t) - I_{ss}^{IBIS}(t) \end{cases}$$

✓ more six I-t curves should be extracted and included to compensate the missing dynamic current, I ^{dyn}_{ss,com}(t), at the ground node.



MODEL NUMERICAL RESULTS

 Validation Setup with three simultaneously switching output buffers



The single driver is designed as a four cascaded inverter with increasing driving capability based on CMOS fully depleted silicon on isolator (FDSOI) technology at 28nm node from STMicroelectronics

✓ Comparison between model's prediction of the $I_{dd}(t)$ and $I_{ss}(t)$



MODEL SIMULATION PERFORMANCE

Comparison between model's prediction of the output voltage $V_2(t)$ at the first output pin.



 ✓ Performance of the Transient Simulation of the proposed Model in the validation setup

Model	NMSE _{Vss}	NMSE _{Vdd}	NMSE _{V2}	CPU time
Transistor Level	-	-	-	95.41 s
Proposed Model	-23.74 dB	-25.1 dB	-27.3 dB	39.76 s

The accurate prediction of the output pin voltage of the first driver is illustrated in this figure. As seen from Table, the developed model speed-up the simulation by 58.33% while keeping acceptable NMSE around -25 dB.

For more results and explanation please see the paper [1]:

[1] W. Dghais, J. Rodriguez "IBIS Model Formulation and Extraction for SPI Evaluation", IEEE workshop on signal and power integrity (SPI), Berlin, Germany, May 2015.

CONCLUSIONS

- ✓ This paper has proposed a complementary extension of the previous IBIS model for SPI evaluations based on BIRDs 95.6 and 98.3.
- ✓ The proposed extraction procedure simplifies the static gate modulation effect and extend the dynamic PG timing I-t, and merges this with the V-t characterization.
- \checkmark The accuracy and computational efficiency of the resulting model was analyzed.
- The achieved results confirm the validity of this method for modelling PG bouncing under the SSO scenario.
- ✓ A slight modification of the two-port characterization procedure of the IBIS model by measuring the $I_{dd}(t)$ and $I_{ss}(t)$ currents instead of $I_2(t)$ will merge both characterization setups for both V-t and I-t waveform extractions in a single step.

REFERENCES

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[1] W. Dghais, J. Rodriguez "IBIS Model Formulation and Extraction for SPI Evaluation", IEEE workshop on signal and power integrity (SPI), Berlin, Germany, May 2015.

[2] I.O. Forum, I/O Buffer Information Specification version 5.1. [Online]. Available: http://eda.org/pub/ibis/ver5.1/ver5_1.pdf, August 2012.

[3] P. Pulici, A. Girardi, G. P. Vanalli, R. Izzi, G. Bernardi, G. Ripamonti, A. G. M. Strollo and G. Campardo "A modified IBIS model aimed at signal integrity analysis of systems in package", IEEE Trans. Circuits Syst. I, Reg. Papers, vol. 55, no. 7, pp.1921-1928 2008.

[4] W. Dghais, H. M. Teixeira, T. R. Cunha, and J. C. Pedro "Novel Extraction of Table-Based I-Q Behavioral Model for High-Speed Digital Buffers/Drivers", IEEE Trans. on Components, Packaging and Manufacturing Technology, March 2013.

[5] W. Dghais, T. R. Cunha, and J. C. Pedro "A Novel Two-Port Behavioral Model for I/O Buffer Overclocking Simulation" IEEE Trans. on Components, Packaging and Manufacturing Technology, October 2013.

[6] Z. Yang , S. Huq , V. Arumugham and I. Park "Enhancement of IBIS modeling capability in simutanous switching noise (SSN) and other power integrity related simulations-proposal, implementation, and validation", Int. Symp. Electromagn. Compatibil., vol. 2, pp.672 -677 2005.

[7] Yingxin Sun and Raymond Y. Chen, "An Advanced Behavioral Buffer Model With Over-Clocking Solution", Cadence, IBIS Asia Summit Shanghai, China, Nov. 15, 2013.

[8] I. S. Stievano, I. A. Maio, F. G. Canavero and C. Siviero "Reliable eye-diagram analysis of data links via device macromodels", IEEE Trans. Adv. Packag., vol. 29, pp.31-38 2006.

[9] W. Dghais, T. R. Cunha, and J. C. Pedro "Reduced-Order Parametric Behavioral Model for Digital Buffers/Drivers with Physical Support", IEEE Trans. on Components, Packaging and Manufacturing Technology, vol. 2, no. 12, pp. 1 - 10, Dec. 2012. [10] W.Dghais, J. Rodriguez "Empirical modelling of FDSOI CMOS Inverter for Signal/Power Integrity Simulation", IEEE Design Automation and Test in Europe (DATE), April 2015.